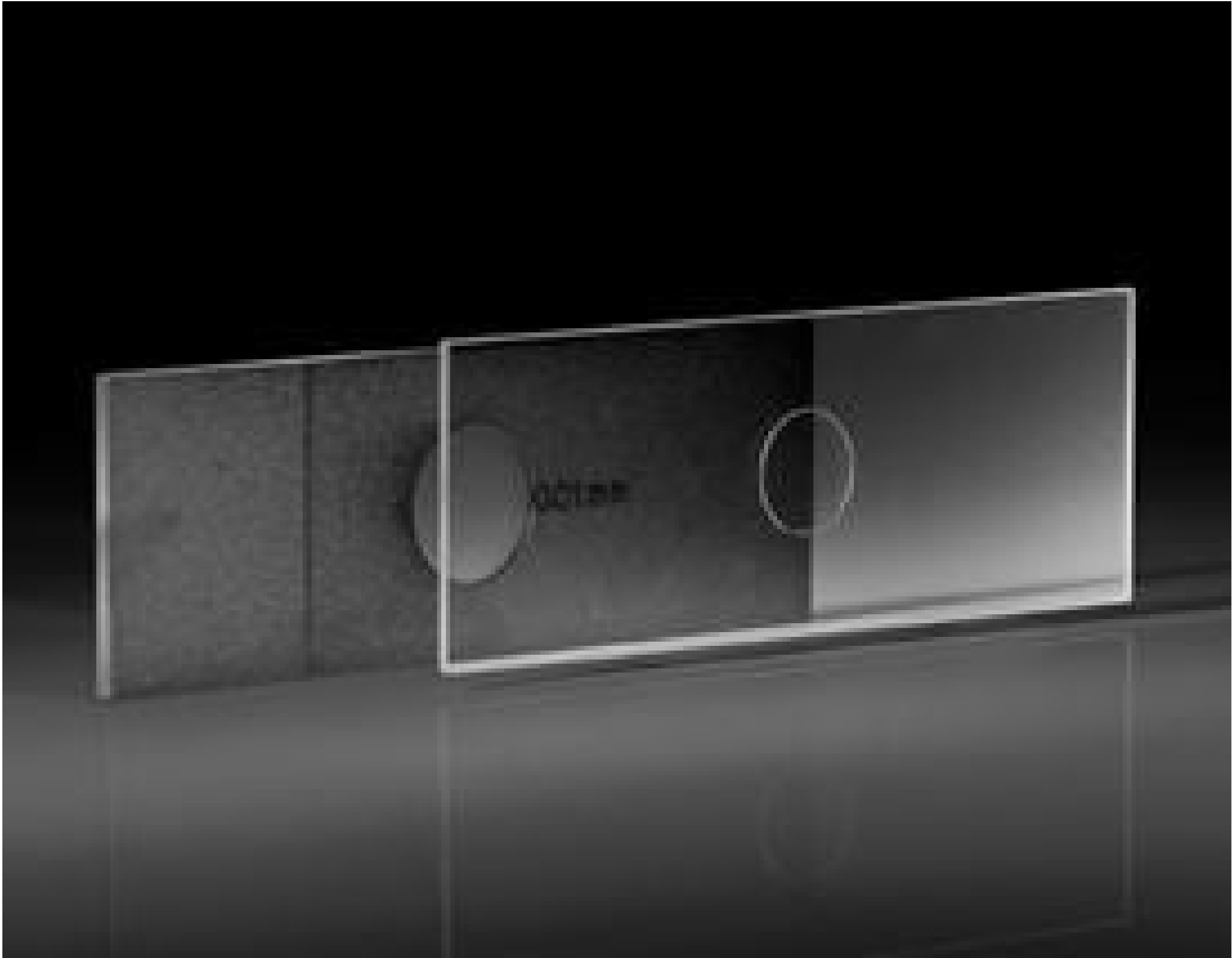


1mm/ 100 Divisions, Stage Micrometer



Stage Micrometers

Stock **#36-121** **9 In Stock**

-

1

+

S\$450⁰⁰

ADD TO CART

Volume Pricing	
Qty 1-4	S\$450.80 each
Qty 5+	S\$429.24 each
Need More?	Request Quote

Product Downloads

Physical & Mechanical Properties

1.10 ±0.1	Thickness (mm):
0.0017	Line Width (mm):
±0.0003	Line Width Tolerance (mm):

Regulatory Compliance

Product Details

- Reticle Scales Centered on Microscope Slides
- Designed for Routine Calibration
- 1 x 3" Slide Sizes

Stage Micrometers are reticle scales centered and mounted on 1" x 3" slides. The micrometers are designed for the routine calibration of microscope eyepiece reticles and objective powers, especially when interchanging objectives or eyepiece reticles between microscopes. The micrometers have a thickness tolerance of ± 0.1 mm. Stage Micrometer model **#36-121** is 1 mm thick on clear glass slides with 10 mm glass disc; all others are 1.5 mm thick with black anodized aluminum slides and 12.5 mm clear aperture for 16 mm diameter glass disc. Model **#36-121** does not have numbered scales.

Stage Micrometers provide precise calibration standards with fine division markings for accurate microscope system alignment and measurement verification. With line widths as fine as 0.001 mm and thickness tolerances of ± 0.1 mm, they support high-accuracy system setups. The durable glass and anodized aluminum constructions ensure reliability for educational, research, and industrial environments.

FAQ(s)

What is the difference between the available Stage Micrometers?

The micrometers mainly vary by division markings and whether they feature a clear glass or anodized aluminum slide for specialized calibration needs.

How precise are the markings on these Stage Micrometers?

Line widths can be as fine as 0.001 mm, and overall accuracy can be down to $\pm 1.00 \mu\text{m}$.

Are NIST certifications available for these micrometers?

These stage micrometers are not NIST-certified but are manufactured to stringent tolerances suitable for various calibration applications.

Technical Information

